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Application/Control No.	Applicant(s)/Patent under Reexamination
10/009,167	NAAMAN ET AL.
Examiner	Art Unit
Christopher M. Babic	1637

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
UPDATED	12/16/2005	СМВ
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